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Application/Control No.	Applicant(s)/Patent under Reexamination
10/074,819	HORN, JAMES VAN
Examiner	Art Unit
Tan Dean D. Nguyen	3629

SEARCHED					
Class	Subclass	Date	Examiner		
705	1	1/0%	Sn		
	8				
235	4720				
	375				
	380	$\bigvee$			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
FOREIGN  1. EPO 2-JPO 3. Dermen	1/06 -	2071		